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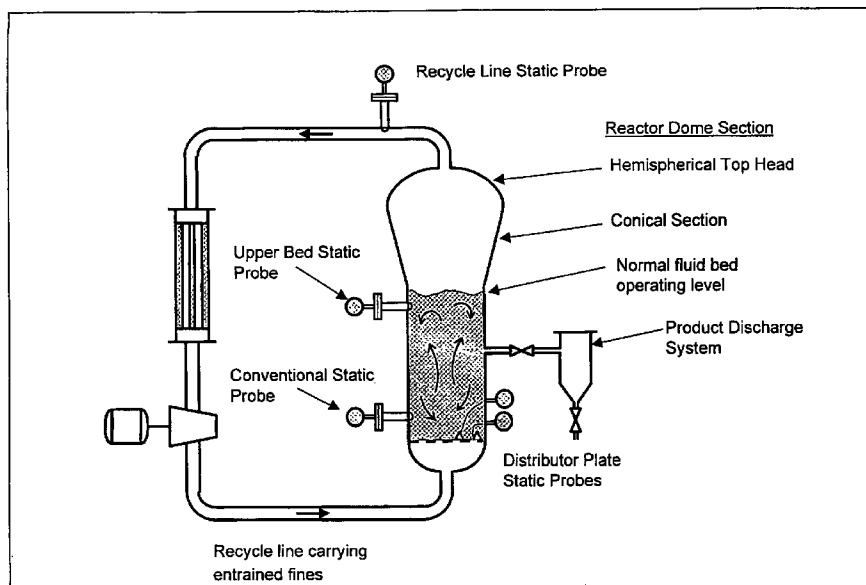
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[Continued on next page]

(54) Title: METHOD FOR CONTROLLING SHEETING IN GAS PHASE REACTORS

Instrument Locations on Pilot-Scale Reactor



(57) Abstract: Embodiments of the present invention relate to measuring and controlling static in a gas phase reactor polymerization. In particular, embodiments relate to monitoring carryover static in an entrainment zone during gas phase polymerization to determine the onset of reactor discontinuity events such as chunking and sheeting. Embodiments also relate to monitoring carryover static to determine the need for effective additions of continuity additives that minimize reactor static activity and thereby preventing discontinuity events.

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**Declarations under Rule 4.17:**

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